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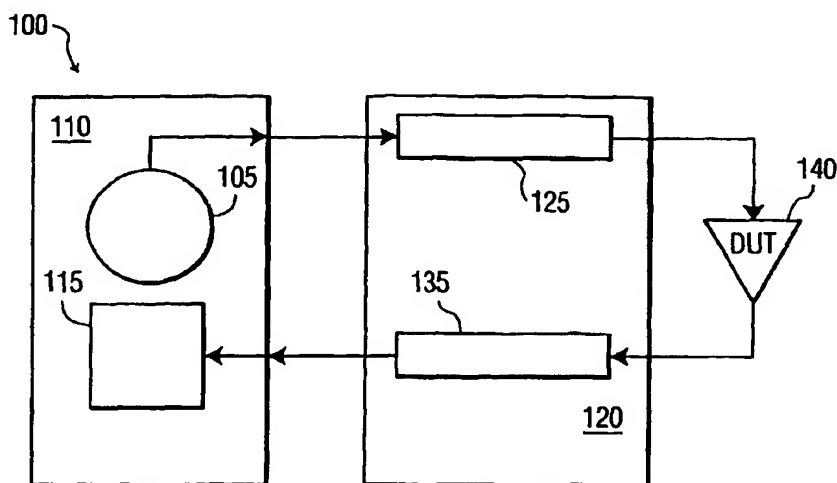
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- (71) Applicant (for all designated States except US): **KONINKLIJKE PHILIPS ELECTRONICS, N.V.** [NL/NL]; Groenewoudseweg 1, NL-5621 BA Eindhoven (NL).
- (72) Inventors; and
- (75) Inventors/Applicants (for US only): **VISSER, Hendrik** [NL/US]; 1109 McKay Drive, M/S-SJ41, San Jose, CA 95131-1706 (US). **SPAIN, Sherry** [US/US]; P.O. Box 3001, Briarcliff Manor, NY 10510-8001 (US).
- (74) Common Representative: **KONINKLIJKE PHILIPS ELECTRONICS, N.V.**; c/o Shannon Lester, 1109 McKay Drive, M/S-SJ41, San Jose, CA 95131-1706 (US).
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(54) Title: CALIBRATION OF TESTER AND TESTBOARD BY GOLDEN SAMPLE



(57) Abstract: In performing testing on Automatic Test Equipment (ATE) it is a challenge to accurately generate and measure RF (radio frequency) power. In an example embodiment, in a test apparatus (100) used for measuring the input and output characteristics of an amplifier (140), there is a method for determining test program parameters. The method (200) comprises calculating input loss from the test apparatus power source to the input of the amplifier (220), defining an input loss correction factor. The output loss from the amplifier output (220) to the power meter of the test apparatus is calculated, defining an output loss correction factor. Using the input loss correction factor (230), a real input power level is determined and using the output loss correction factor (230), a real output level is determined.

**Declarations under Rule 4.17:**

- as to applicant's entitlement to apply for and be granted a patent (Rule 4.17(ii)) for the following designations AE, AG, AL, AM, AT, AU, AZ, BA, BB, BG, BR, BW, BY, BZ, CA, CH, CN, CO, CR, CU, CZ, DE, DK, DM, DZ, EC, EE, EG, ES, FI, GB, GD, GE, GH, GM, HR, HU, ID, IL, IN, IS, JP, KE, KG, KP, KR, KZ, LC, LK, LR, LS, LT, LU, LV, MA, MD, MG, MK, MN, MW, MX, MZ, NA, NI, NO, NZ, OM, PG, PH, PL, PT, RO, RU, SC, SD, SE, SG, SK, SL, SY, TJ, TM, TN, TR, TT, TZ, UA, UG, UZ, VC, VN, YU, ZA, ZM, ZW, ARIPO patent (BW, GH, GM, KE, LS, MW, MZ, NA, SD, SL, SZ, TZ, UG, ZM, ZW), Eurasian patent (AM, AZ, BY, KG, KZ, MD, RU, TJ, TM), European patent (AT, BE, BG, CH, CY, CZ, DE, DK, EE, ES, FI, FR, GB, GR, HU, IE, IT, LU, MC, NL, PL, PT, RO, SE, SI, SK, TR), OAPI patent (BF, BJ, CF, CG, CI, CM, GA, GN, GQ, GW, ML, MR, NE, SN, TD, TG)

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